

Dr. Burkhard Beckhoff is head of the X-ray spectrometry group at PTB, Germany's national metrology institute. He studied physics in Germany and France. After his PhD in physics, he joined the PTB department of metrology with synchrotron radiation where he developed various research activities in the field of surface and interface characterisation of nanoscale samples from nanoelectronics, biotechnology, energy conversion and storage. He was involved in the acquisition of more than 20 European (FP6, Horizon, EMPIR, EPM) and 10 German (DFG, BMBF, MN PQ, WIPANO) research projects, several of which he coordinated. He was initiator and co-organiser of the ALTECH symposia on techniques for the characterisation of nanomaterials at the E-MRS Spring Meetings 2014 to 2024, co-editor of the Springer handbook "Handbook of Practical X-ray Fluorescence Analysis" and co-organiser of the international roadmap generation of the "International Initiative on X-Ray Fundamental Parameters" (www.exsa.hu/fpi.php). Since 2000, he has been co-organiser of the research seminar "Modern Analytical Methods in Physics" at the Technical University of Berlin (TUB). In 2018 he received the "outstanding career award" of the European X-ray Spectrometry Association (EXSA) and in 2026 the "Birks Award" of the Denver X-Ray conference. Since 2022 he is convenor of the standardisation committee ISO/TC 201 (Surface Chemical Analysis) SG2 (Energy materials).